


<b>Search Notes</b>  	<b>Application/Control No.</b>  10824434	<b>Applicant(s)/Patent Under Reexamination</b>  YOON ET AL.
	<b>Examiner</b>  Tan, Alvin H	<b>Art Unit</b>  2173

SEARCHED			
Class	Subclass	Date	Examiner
715	744, 747	5/3/07 (Updated 11/20/08)	/AT/ (/AT/)

SEARCH NOTES		
Search Notes	Date	Examiner
715/744-747 (text search only - see search history printout)	5/3/07 (Updated 11/20/08)	/AT/ (/AT/)
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	5/3/07 (Updated 11/20/08)	/AT/ (/AT/)
NPL - ACM Portal	5/4/07	AT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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